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- State-of-the-Art *EPIC-IIB™* BiCMOS Design Significantly Reduces Power Dissipation
- **ESD Protection Exceeds 2000 V Per** MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 500 mA Per **JEDEC Standard JESD-17**
- Typical V_{OLP} (Output Ground Bounce) < 1 V at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$
- **High-Impedance State During Power Up** and Power Down
- High-Drive Outputs (-32-mA I_{OH}, 64-mA I_{OL})
- **Package Options Include Plastic** Small-Outline (DW), Shrink Small-Outline (DB), and Thin Shrink Small-Outline (PW) Packages, Ceramic Chip Carriers (FK), Ceramic Flat (W) Package, and Plastic (NT) and Ceramic (JT) DIPs

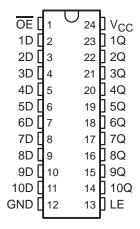
description

The SN54ABT841 and SN74ABT841A 10-bit latches are designed specifically for driving highly capacitive or relatively low-impedance loads. They are particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

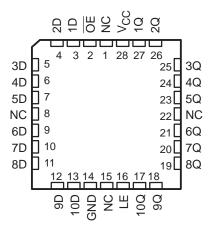
The ten transparent D-type latches provide true data at their outputs.

A buffered output-enable (\overline{OE}) input can be used to place the ten outputs in either a normal logic state (high or low logic levels) or a high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without need for interface or pullup components.

SN54ABT841 . . . JT OR W PACKAGE SN74ABT841A...DB, DW, NT, OR PW PACKAGE (TOP VIEW)



SN54ABT841 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

OE does not affect the internal operations of the latch. Previously stored data can be retained or new data can be entered while the outputs are in the high-impedance state.

When V_{CC} is between 0 and 2.1 V, the device is in the high-impedance state during power up or power down. However, to ensure the high-impedance state above 2.1 V, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN54ABT841 is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74ABT841A is characterized for operation from -40°C to 85°C.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

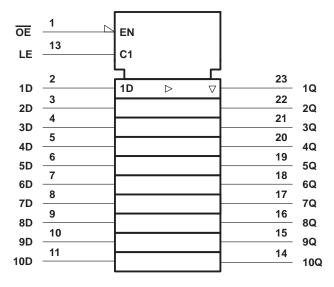
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FUNCTION TABLE

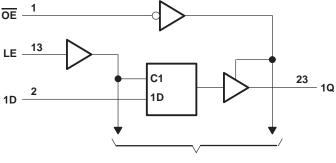
	INPUTS	OUTPUT	
Œ	LE	D	Q
L	Н	Н	Н
L	Н	L	L
L	L	Χ	Q ₀
Н	Χ	Χ	Z

logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the DB, DW, JT, NT, PW, and W packages.

logic diagram (positive logic)



To Seven Other Channels

Pin numbers shown are for the DB, DW, JT, NT, PW, and W packages.

SN54ABT841, SN74ABT841A 10-BIT BUS-INTERFACE D-TYPE LATCHES WITH 3-STATE OUTPUTS

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage range, V _{CC}		0.5 V to 7 V
Input voltage range, V _I (see Note 1)		
Voltage range applied to any output in the high	or power-off state, V _O	0.5 V to 5.5 V
Current into any output in the low state, Io: SNS	54ABT841	96 mA
SN	74ABT841A	128 mA
Input clamp current, I _{IK} (V _I < 0)		–18 mA
Output clamp current, I _{OK} (V _O < 0)		–50 mA
Package thermal impedance, θ_{JA} (see Note 2):	DB package	104°C/W
	DW package	81°C/W
	NT package	67°C/W
	PW package	120°C/W
Storage temperature range, T _{stq}		-65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

2. The package thermal impedance is calculated in accordance with EIA/JEDEC Std JESD51, except for through-hole packages, which use a trace length of zero.

recommended operating conditions (see Note 3)

		SN54ABT841		SN74ABT841A		UNIT
		MIN	MAX	MIN	MAX	UNII
Vcc	Supply voltage	4.5	5.5	4.5	5.5	V
VIH	High-level input voltage	2		2		V
V _{IL}	Low-level input voltage		0.8		0.8	V
VI	Input voltage	0	VCC	0	VCC	V
IOH	High-level output current		-24		-32	mA
lOL	Low-level output current		48		64	mA
Δt/Δν	Input transition rise or fall rate		5		5	ns/V
Δt/ΔV _{CC}	Power-up ramp rate	200		200		μs/V
T _A	Operating free-air temperature	-55	125	-40	85	°C

NOTE 3: Unused inputs must be held high or low to prevent them from floating.



SN54ABT841, SN74ABT841A 10-BIT BUS-INTERFACE D-TYPE LATCHES WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED	TEST CONDITIONS		Т	A = 25°C	;	SN54A	BT841	SN74ABT841A		UNIT	
PARAMETER	TEST CONDIT	IONS	MIN	TYP†	MAX	MIN	MAX	MIN	MAX	UNII	
VIK	V _{CC} = 4.5 V,	I _I = -18 mA			-1.2		-1.2		-1.2	V	
	$V_{CC} = 4.5 \text{ V},$	$I_{OH} = -3 \text{ mA}$	2.5			2.5		2.5			
Vou	V _{CC} = 5 V,	$I_{OH} = -3 \text{ mA}$	3			3		3		V	
VOH	V _{CC} = 4.5 V	$I_{OH} = -24 \text{ mA}$	2			2				V	
	VCC = 4.5 V	$I_{OH} = -32 \text{ mA}$	2*					2			
VOL	V _{CC} = 4.5 V	I _{OL} = 48 mA			0.55		0.55			V	
VOL.	VCC = 4.5 V	$I_{OL} = 64 \text{ mA}$			0.55*				0.55		
V _{hys}				100						mV	
ΙΙ	$V_{CC} = 0 \text{ to } 5.5 \text{ V},$	$V_I = V_{CC}$ or GND			±1		±1		±1	μΑ	
lozpu‡	$V_{CC} = 0 \text{ to } 2.1 \text{ V}, V_{O} = 0.5 \text{ V to } 2.7 \text{ V}, \overline{OE} = X$				±50		±50		±50	μΑ	
l _{OZPD} ‡	$V_{CC} = 2.1 \text{ V to } 0, V_{O} = 0.5 \text{ V to } 2.7 \text{ V}, \overline{OE} = X$				±50		±50		±50	μΑ	
lozh	$V_{CC} = 2.1 \text{ V to } 5.5 \text{ V}, V_{O} = 2.7 \text{ V}, \overline{OE} \ge 2 \text{ V}$				10		10		10	μΑ	
lozL	$V_{CC} = 2.1 \text{ V to } 5.5 \text{ V}, V_{O} = 0.5 \text{ V}$	5 V, OE ≥ 2 V			-10		-10		-10	μΑ	
l _{off}	$V_{CC} = 0$,	V_I or $V_O \le 4.5 \text{ V}$			±100				±100	μΑ	
ICEX	$V_{CC} = 5.5 \text{ V}, V_{O} = 5.5 \text{ V}$	Outputs high			50		50		50	μΑ	
IO§	V _{CC} = 5.5 V,	V _O = 2.5 V	-50	-140	-180	-50	-180	-50	-180	mA	
	.,	Outputs high		1**	250**		280		250	μΑ	
Icc	$V_{CC} = 5.5 \text{ V, I}_{O} = 0,$ $V_{I} = V_{CC} \text{ or GND}$	Outputs low		24**	38¶**		45¶		38¶	mA	
	V1 = V00 01 011B	Outputs disabled		0.5**	250**		280		250	μΑ	
	V _{CC} = 5.5 V, One input at 3.4 V,	Outputs enabled			1.5		1.5		1.5	mA	
∆lcc#		Outputs disabled			250**		280		250	μΑ	
	Other inputs at V _{CC} or GND	Control inputs			1.5		1.5		1.5	mA	
C _i	V _I = 2.5 V or 0.5 V			4						pF	
Co	V _O = 2.5 V or 0.5 V			7						pF	

^{*} On products compliant to MIL-PRF-38535, this parameter does not apply.

timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

				$V_{CC} = 5 \text{ V},$ $T_A = 25^{\circ}C$		SN54ABT841		SN74ABT841A	
			MIN	MAX	MIN	MAX	MIN	MAX	
t _W	Pulse duration, LE high or low		3.3		3.3		3.3		ns
	Setup time, data before LE↓	High	2.5		2.5		2.5	2.5	ns
t _{su}	Setup time, data before LEV	Low	1.5		1.5		1.5		
Ţ.	Hold time, data after LE↓	High	1.5		1.5		1.5		ns
t _h Hold time, data after LE↓	Floid time, data after LLV	Low	1.5		2		1.5		115



^{**} These limits apply only to the SN74ABT841A.

[†] All typical values are at $V_{CC} = 5 \text{ V}$.

[‡] This parameter is characterized, but not production tested.

[§] Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

[¶] This limit may vary among suppliers.

[#]This is the increase in supply current for each input that is at the specified TTL voltage level rather than VCC or GND.

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switching characteristics over recommended ranges of supply voltage and operating free-air temperature, C_L = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _C	C = 5 V \ = 25°C	<u>'</u> ,	MIN	MAX	UNIT
			MIN	TYP	MAX			
t _{PLH}	D	Q	1†	4.1	5.5	1†	6.8	ns
^t PHL			1.5†	4	5.5	1.5†	6.8	115
t _{PLH}	LE	Q	1.6†	4.1	6.6†	1.6†	7.4	20
t _{PHL}		L Q	2†	4.6	6.2	2†	6.8	ns
^t PZH	ŌĒ	Q	1	3	4.9†	1	5.8	20
tPZL	OE	<u> </u>	2.2	4.1	5.7	2.2	6.5	ns
^t PHZ		Q	2†	4.7	6.2	2†	7.2	ns
t _{PLZ}	ŌĒ		1.5†	4.6	6.1	1.5†	6.6	115

[†] This data sheet limit may vary among suppliers.

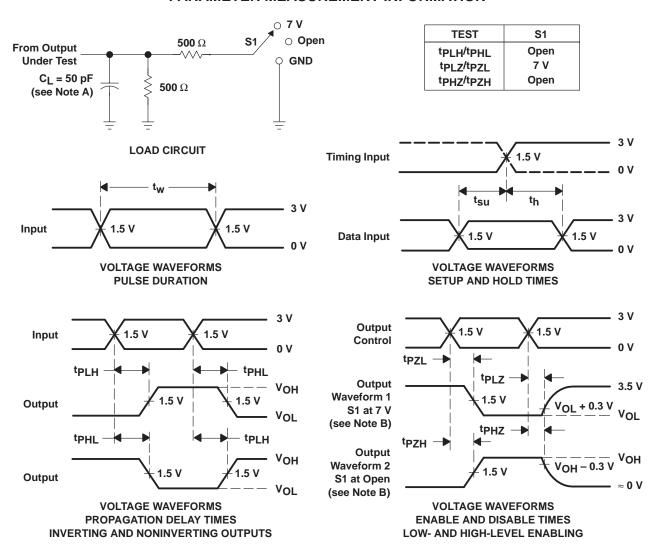
switching characteristics over recommended ranges of supply voltage and operating free-air temperature, C_L = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V ₍	CC = 5 V 4 = 25°C	/, ;	MIN	MAX	UNIT
			MIN	TYP	MAX			
t _{PLH}	D	Q	1.4†	4.1	5.5	1.4†	6.2†	ns
t _{PHL}			1.5†	4	5.5	1.5†	6.2	115
t _{PLH}		Q	2.1†	4.1	5.9†	2.1†	6.5†	ns
^t PHL	LE	Q .	2.4†	4.6	6.2	2.4†	6.7	115
^t PZH	ŌĒ	Q	1	3	4.7	1	5.3†	20
tPZL	OE OE	Q	2.2	4.1	5.7	2.2	6.3†	ns
^t PHZ	ŌĒ	Q	2.6†	4.7	6.2	2.6†	7.1	ns
^t PLZ	OE	Q	1.9†	4.6	6.1	1.9†	6.5	115

[†] This data sheet limit may vary among suppliers.

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PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_{Q} = 50 Ω , t_{f} \leq 2.5 ns, t_{f} \leq 2.5 ns.
- D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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